

Notice of References Cited

Application/Control No.

10/716,879

Applicant(s)/Patent Under
Reexamination
SCHEIER ET AL.

Examiner

Alex Liew

Art Unit

2624

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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*	B	US-5,453,762	09-1995	Ito et al.	345/179
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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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